Use of 2D X-ray Detector in Powder Diffraction Measurement

Takashi Ida, Shoki Ono, Daiki Hattan, Kento Wachi, Hisashi Hibino Advanced Ceramics Research Center, Nagoya Institute of Technology

Introduction

We can now use 2D X-ray detectors.

Question 1:

Are 2D data useful for powder diffraction ?

Question 2:

How should the 2D powder instrument be designed ? Question 3:

How can we treat 2D powder diffraction data ?



Hull [1] Photograph



Dectris PILATUS 100K (172 µm pixel)



Rigaku HyPix-3000 (100 µm pixel)



BrukerAXS VÅNTEC-500



PANalytical PIXcel

(68 µm pixel)

(55 µm pixel)

Fig. 1 2D X-ray detectors



Fig. 2 Schematic configuration of AichiSR BL5S2 beam line optics



Fig. 4 Straight formation of 4-Pilatus detectors on the AichiSR BL5S2 beam line. Camera length : 340 mm – 1000 mm



Fig. 5 NIST SRM660b LaB₆ profile synthesized by 3-shot (1 min / each) data of 4 Pilatus detectors on the AichiSR BL5S2 beam line.





Fig. 6 One-shot (off-center) formation of 4-Pilatus detectors on the AichiSR BL5S2 beam line. Camera length : 170 mm

Advantages of flat 2D detectors

(1) Rapid measurement

- Getting more pronounced

(2) Free of aberration

Integration along Debye-Scherrer or Hull rings.
Combination with convergent synchrotron beam is particularly effective.

Disadvantages of flat 2D detectors

- (1) Higher cost
- Getting more reasonable
- (2) Lower angular resolution
- Getting improved.

(3) Error estimation available

- Statistical errors can be evaluated by experiment [2].

 Maximum likelihood estimation can be achieved just by weighted least-squares method.

(3) Higher background

- Probably unavoidable
- Reducible by elimination of stray-light or use of evacuated or He-filled path ?

(4) Mapping to 1D data required

– Automatic method has already been proposed [2,3].

(5) Difficulty in adjustment and/or calibration

- Calibration method is under development.

References

[1] A. W. Hull, *Phys. Rev.* **10**, 661–697 (1917). [2] T. Ida, *Powder Diffr*. (submitted). [3] S. N. Sulyanov, A. N. Popov & D. M. Kheiker, *J. Appl. Cryst.* **27**, 934–942 (1994).